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## IRFR3711ZPbF IRFU3711ZPbF

#### **Applications**

- High Frequency Synchronous Buck Converters for Computer Processor Power
- High Frequency Isolated DC-DC Converters with Synchronous Rectification for Telecom and Industrial Use
- Lead-Free

#### HEXFET® Power MOSFET

V <sub>DSS</sub>	R <sub>DS(on)</sub> max	Qg
20V	5.7m $\Omega$	18nC



D-Pak IRFR3711Z I-Pak IRFU3711Z

#### **Benefits**

- Very Low RDS(on) at 4.5V V<sub>GS</sub>
- Ultra-Low Gate Impedance
- Fully Characterized Avalanche Voltage and Current

**Absolute Maximum Ratings** 

Parameter		Max.	Units	
V <sub>DS</sub>	Drain-to-Source Voltage	20	V	
V <sub>GS</sub>	Gate-to-Source Voltage	± 20		
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	93@		
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	66④	А	
I <sub>DM</sub>	Pulsed Drain Current ①	370		
P <sub>D</sub> @T <sub>C</sub> = 25°C	Maximum Power Dissipation ®	79	W	
P <sub>D</sub> @T <sub>C</sub> = 100°C	Maximum Power Dissipation ®	39	7	
	Linear Derating Factor	0.53	W/°C	
TJ	Operating Junction and	-55 to + 175	°C	
T <sub>STG</sub>	Storage Temperature Range			
·	Soldering Temperature, for 10 seconds	300 (1.6mm from case)		

#### **Thermal Resistance**

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		1.9	
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount) <sup>⑤</sup>		50	°C/W
$R_{\theta JA}$	Junction-to-Ambient		110	

Notes ① through ⑤ are on page 11

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#### Static @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
BV <sub>DSS</sub>	Drain-to-Source Breakdown Voltage	20			٧	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		13		mV/°C	Reference to 25°C, I <sub>D</sub> = 1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		4.5	5.7	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 15A ③
			6.2	7.8		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 12A ③
V <sub>GS(th)</sub>	Gate Threshold Voltage	1.55	2.0	2.45	٧	$V_{DS} = V_{GS}, I_D = 250 \mu A$
$\Delta V_{GS(th)}/\Delta T_J$	Gate Threshold Voltage Coefficient		-5.4		mV/°C	
I <sub>DSS</sub>	Drain-to-Source Leakage Current			1.0	μΑ	$V_{DS} = 16V, V_{GS} = 0V$
				150		$V_{DS} = 16V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I <sub>GSS</sub>	Gate-to-Source Forward Leakage			100	nA	V <sub>GS</sub> = 20V
	Gate-to-Source Reverse Leakage			-100	1	V <sub>GS</sub> = -20V
gfs	Forward Transconductance	48			S	$V_{DS} = 10V, I_D = 12A$
$Q_g$	Total Gate Charge		18	27		
Q <sub>gs1</sub>	Pre-Vth Gate-to-Source Charge		5.1			$V_{DS} = 10V$
Q <sub>gs2</sub>	Post-Vth Gate-to-Source Charge		1.8		nC	$V_{GS} = 4.5V$
$Q_{gd}$	Gate-to-Drain Charge		6.5			I <sub>D</sub> = 12A
$Q_{godr}$	Gate Charge Overdrive		4.6			See Fig. 16
Q <sub>sw</sub>	Switch Charge (Q <sub>gs2</sub> + Q <sub>gd</sub> )		8.3			
Q <sub>oss</sub>	Output Charge		9.8		nC	$V_{DS} = 10V, V_{GS} = 0V$
t <sub>d(on)</sub>	Turn-On Delay Time		12			V <sub>DD</sub> = 15V, V <sub>GS</sub> = 4.5V③
t <sub>r</sub>	Rise Time		13			I <sub>D</sub> = 12A
t <sub>d(off)</sub>	Turn-Off Delay Time		15		ns	Clamped Inductive Load
t <sub>f</sub>	Fall Time		5.2			
C <sub>iss</sub>	Input Capacitance		2160			V <sub>GS</sub> = 0V
C <sub>oss</sub>	Output Capacitance		700		pF	$V_{DS} = 10V$
C <sub>rss</sub>	Reverse Transfer Capacitance		360			f = 1.0MHz

#### **Avalanche Characteristics**

	Parameter	Тур.	Max.	Units
E <sub>AS</sub>	Single Pulse Avalanche Energy <sup>②</sup>		140	mJ
I <sub>AR</sub>	Avalanche Current ①		12	Α
E <sub>AR</sub>	Repetitive Avalanche Energy ①		7.9	mJ

#### **Diode Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			93@		MOSFET symbol
	(Body Diode)				Α	showing the
I <sub>SM</sub>	Pulsed Source Current			370		integral reverse
	(Body Diode) ①					p-n junction diode.
$V_{SD}$	Diode Forward Voltage			1.0	٧	$T_J = 25$ °C, $I_S = 12A$ , $V_{GS} = 0V$ ③
t <sub>rr</sub>	Reverse Recovery Time		19	28	ns	$T_J = 25$ °C, $I_F = 12A$ , $V_{DD} = 10V$
Q <sub>rr</sub>	Reverse Recovery Charge		9.4	14	nC	di/dt = 100A/μs ③
t <sub>on</sub>	Forward Turn-On Time	Intrinsio	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)			

## IRFR/U3711ZPbF

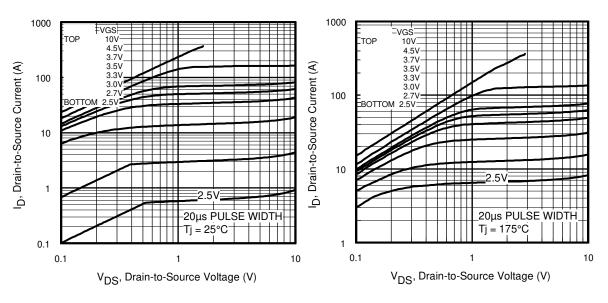


Fig 1. Typical Output Characteristics

Fig 2. Typical Output Characteristics

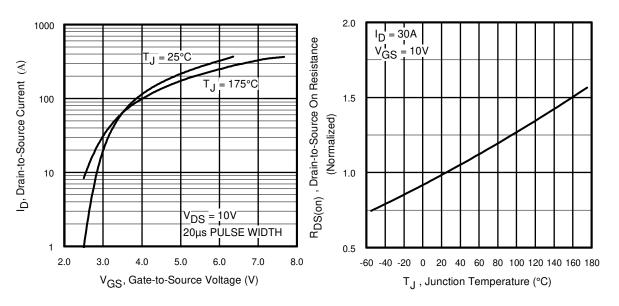
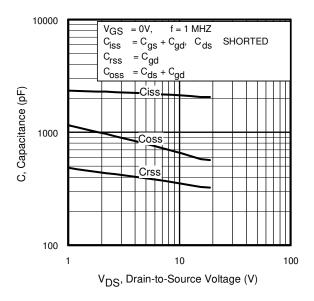


Fig 3. Typical Transfer Characteristics

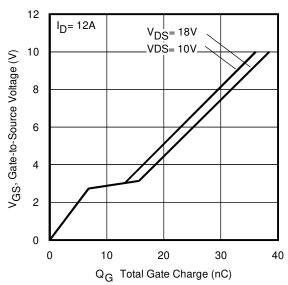
Fig 4. Normalized On-Resistance vs. Temperature

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**Fig 5.** Typical Capacitance vs. Drain-to-Source Voltage



**Fig 6.** Typical Gate Charge vs. Gate-to-Source Voltage

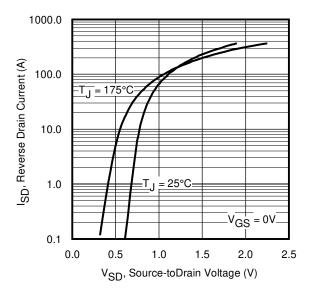


Fig 7. Typical Source-Drain Diode Forward Voltage

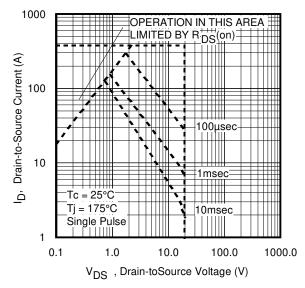
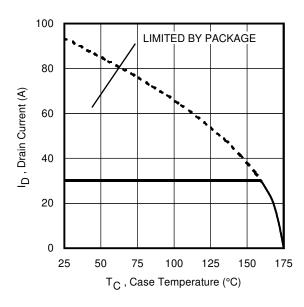


Fig 8. Maximum Safe Operating Area

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2.5 (£)  $\frac{2.0}{1.5}$  0.5  $\frac{1}{1.0} = 250 \mu A$  1.0  $\frac{1}{1.0} = 250 \mu A$  1.0  $\frac{1}{1.0} = 250 \mu A$  1.7  $\frac{1}{1.0} = 250 \mu A$  1.0  $\frac{1}{1.0} = 250$ 

Fig 9. Maximum Drain Current vs.
Case Temperature

Fig 10. Threshold Voltage vs. Temperature

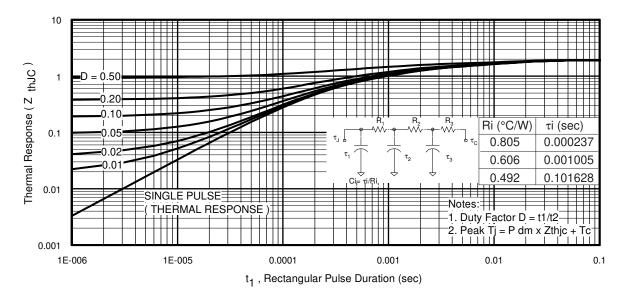


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

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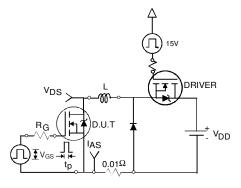


Fig 12a. Unclamped Inductive Test Circuit

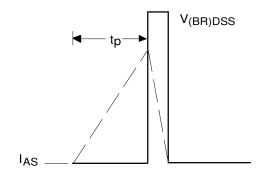


Fig 12b. Unclamped Inductive Waveforms

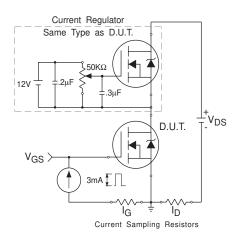


Fig 13. Gate Charge Test Circuit

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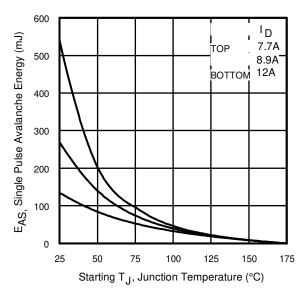


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

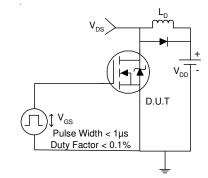


Fig 14a. Switching Time Test Circuit

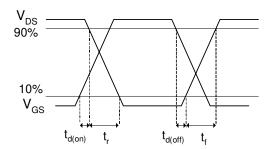


Fig 14b. Switching Time Waveforms

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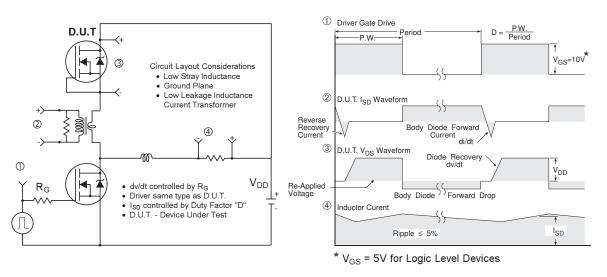


Fig 15. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

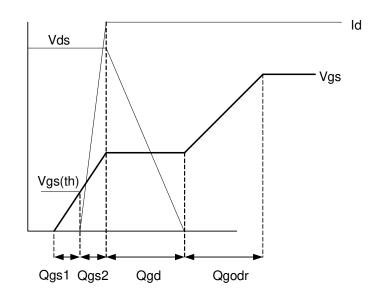


Fig 16. Gate Charge Waveform

#### Power MOSFET Selection for Non-Isolated DC/DC Converters

#### **Control FET**

Special attention has been given to the power losses in the switching elements of the circuit - Q1 and Q2. Power losses in the high side switch Q1, also called the Control FET, are impacted by the  $R_{\rm ds(on)}$  of the MOSFET, but these conduction losses are only about one half of the total losses.

Power losses in the control switch Q1 are given by;

$$P_{loss} = P_{conduction} + P_{switching} + P_{drive} + P_{output}$$

This can be expanded and approximated by;

$$\begin{split} P_{loss} &= \left(I_{rms}^{2} \times R_{ds(on)}\right) \\ &+ \left(I \times \frac{Q_{gd}}{i_{g}} \times V_{in} \times f\right) + \left(I \times \frac{Q_{gs2}}{i_{g}} \times V_{in} \times f\right) \\ &+ \left(Q_{g} \times V_{g} \times f\right) \\ &+ \left(\frac{Q_{oss}}{2} \times V_{in} \times f\right) \end{split}$$

This simplified loss equation includes the terms  ${\rm Q_{gs2}}$  and  ${\rm Q_{oss}}$  which are new to Power MOSFET data sheets.

 $Q_{gs2}$  is a sub element of traditional gate-source charge that is included in all MOSFET data sheets. The importance of splitting this gate-source charge into two sub elements,  $Q_{gs1}$  and  $Q_{gs2}$ , can be seen from Fig 16.

 $Q_{gs2}$  indicates the charge that must be supplied by the gate driver between the time that the threshold voltage has been reached and the time the drain current rises to  $I_{dmax}$  at which time the drain voltage begins to change. Minimizing  $Q_{gs2}$  is a critical factor in reducing switching losses in Q1.

 $\rm Q_{oss}$  is the charge that must be supplied to the output capacitance of the MOSFET during every switching cycle. Figure A shows how  $\rm Q_{oss}$  is formed by the parallel combination of the voltage dependant (nonlinear) capacitance's  $\rm C_{ds}$  and  $\rm C_{dg}$  when multiplied by the power supply input buss voltage.

#### Synchronous FET

The power loss equation for Q2 is approximated by;

$$\begin{split} P_{loss} &= P_{conduction} + P_{drive} + P_{output}^* \\ P_{loss} &= \left(I_{rms}^2 \times R_{ds(on)}\right) \\ &+ \left(Q_g \times V_g \times f\right) \\ &+ \left(\frac{Q_{oss}}{2} \times V_{in} \times f\right) + \left(Q_{rr} \times V_{in} \times f\right) \end{split}$$

\*dissipated primarily in Q1.

For the synchronous MOSFET Q2,  $R_{\rm ds(on)}$  is an important characteristic; however, once again the importance of gate charge must not be overlooked since it impacts three critical areas. Under light load the MOSFET must still be turned on and off by the control IC so the gate drive losses become much more significant. Secondly, the output charge  $Q_{\rm oss}$  and reverse recovery charge  $Q_{\rm rr}$  both generate losses that are transfered to Q1 and increase the dissipation in that device. Thirdly, gate charge will impact the MOSFETs' susceptibility to Cdv/dt turn on.

The drain of Q2 is connected to the switching node of the converter and therefore sees transitions between ground and  $V_{\rm in}.$  As Q1 turns on and off there is a rate of change of drain voltage dV/dt which is capacitively coupled to the gate of Q2 and can induce a voltage spike on the gate that is sufficient to turn the MOSFET on, resulting in shoot-through current . The ratio of  $Q_{\rm gd}/Q_{\rm gs1}$  must be minimized to reduce the potential for Cdv/dt turn on.

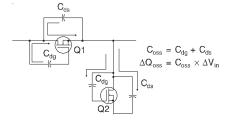
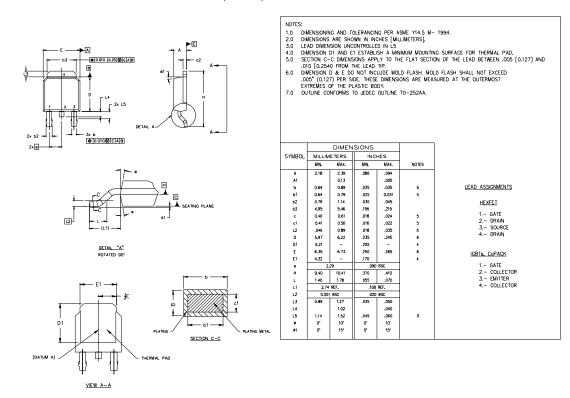


Figure A: Qoss Characteristic

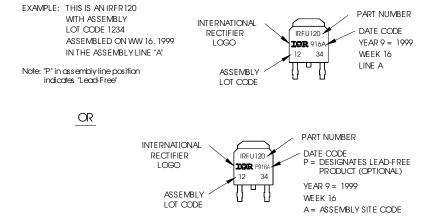
#### IRFR/U3711ZPbF

#### D-Pak (TO-252AA) Package Outline

Dimensions are shown in millimeters (inches)



#### D-Pak (TO-252AA) Part Marking Information

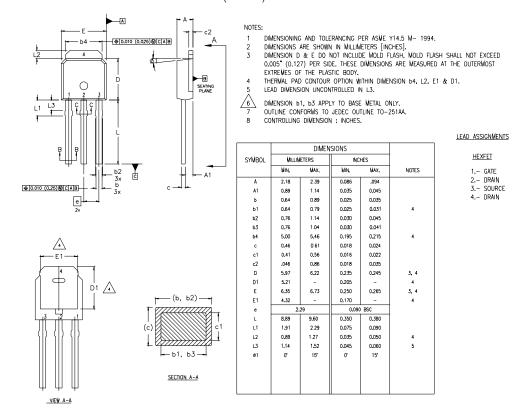


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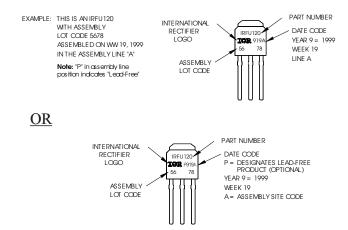
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#### I-Pak (TO-251AA) Package Outline

Dimensions are shown in millimeters (inches)

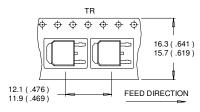


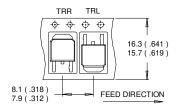
### I-Pak (TO-251AA) Part Marking Information



#### D-Pak (TO-252AA) Tape & Reel Information

Dimensions are shown in millimeters (inches)





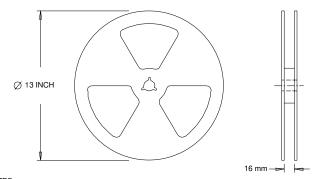
#### NOTES

- NOTES:

  1. CONTROLLING DIMENSION: MILLIMETER.

  2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).

  3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES: 1. OUTLINE CONFORMS TO EIA-481.

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Starting  $T_J = 25$ °C, L = 1.9mH,  $R_G = 25\Omega$ ,  $I_{AS} = 12A$ .
- ③ Pulse width  $\leq 400 \mu s$ ; duty cycle  $\leq 2\%$ .
- junction temperature. Package limitation current is 30A.
- ⑤ When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.

Data and specifications subject to change without notice. This product has been designed and qualified for the Industrial market. Qualification Standards can be found on IR's Web site.



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Note: For the most current drawings please refer to the IR website at: <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>